

FIG . 1

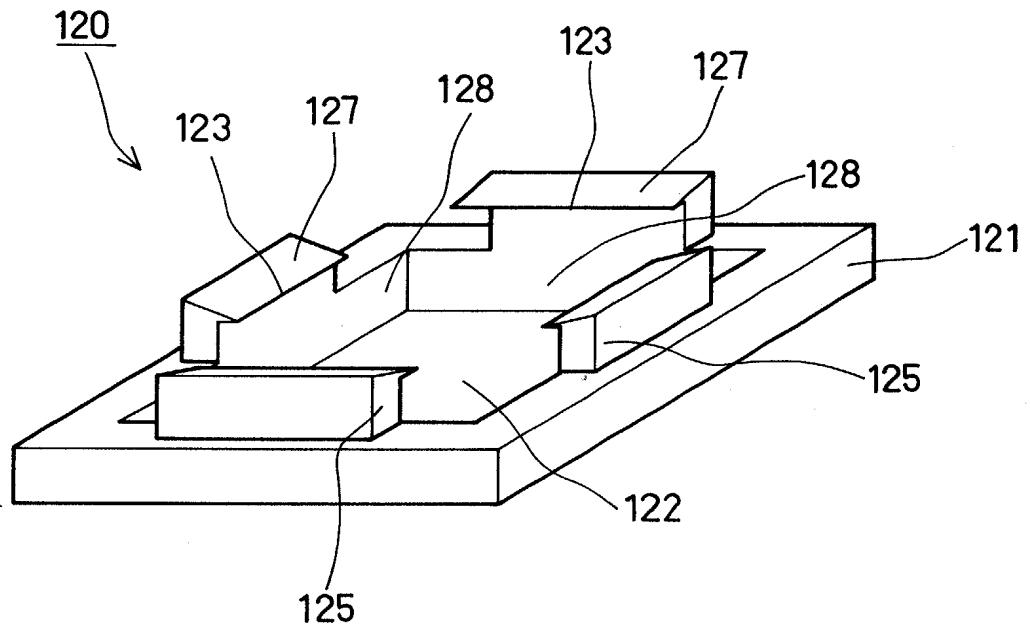


FIG.2

This diagram shows a cross-sectional view of a semiconductor device assembly. A substrate 101 is shown at the bottom. On top of the substrate, there are several layers and structures. A layer 102 is on the substrate. Above it is a layer 104. On top of layer 104, there are two main structures. On the left, there is a structure 225 with a top layer 220 and a side layer 227. A layer 223 is on top of 220. A layer 228 is on the side of 225. On the right, there is a similar structure 221 with a top layer 220, a side layer 227, and a layer 223 on top. A layer 228 is also on the side of 221. A central layer 105 is located between the two main structures. A layer 106 is located between the two main structures, below layer 105. A layer 104 is also shown at the bottom of the central structure.

FIG. 3

Figure 1. Schematic diagram of the experimental setup. The subjects were seated in a dimly lit room and viewed the screen through a mirror. The screen displayed the target and the starting position of the hand. The hand was moved from the starting position to the target position. The distance between the starting position and the target position was 10 cm. The hand was moved at a constant velocity. The time taken for the hand to reach the target was recorded. The experiment was controlled using a personal computer.

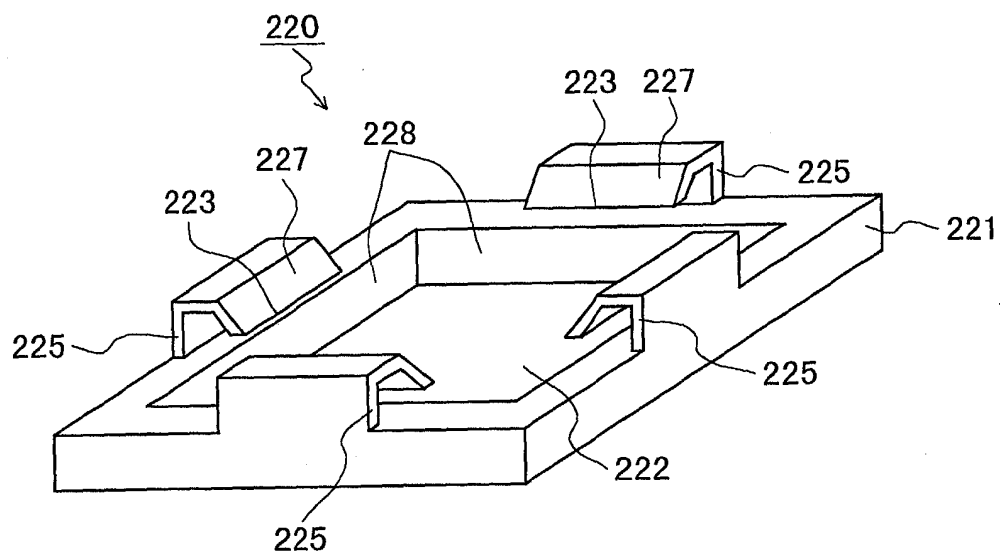


FIG. 4

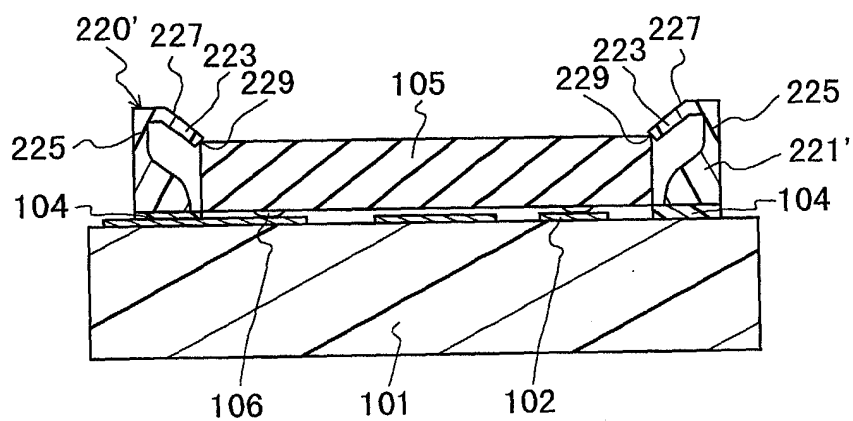


FIG. 5

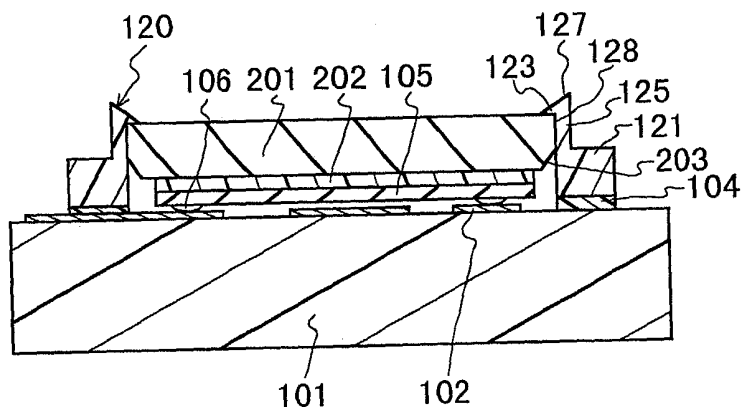


FIG . 6

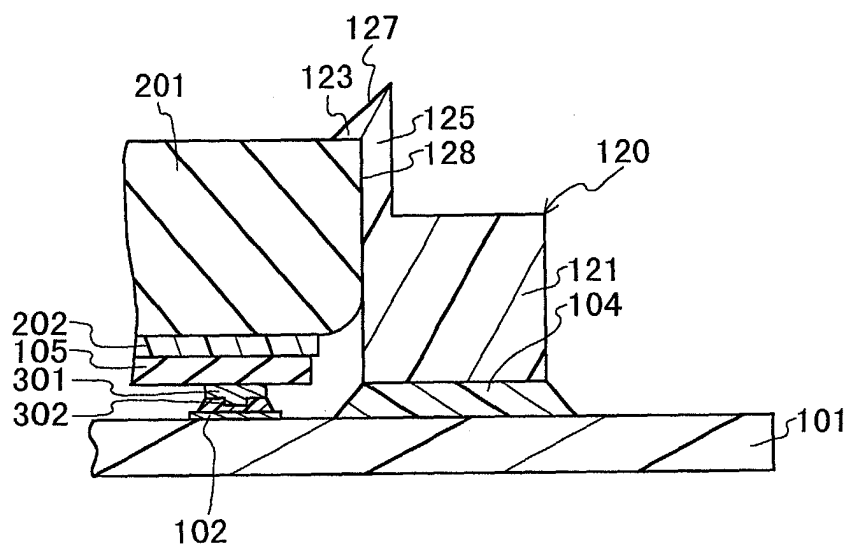


FIG . 7